

Product Specification for Approval

CUSTOMER : 麗臺科技股份有限公司

PART NO. : CBA-0804-2G4S2-A1

DESCRIPTION: CHIP ANTENNA

DATE : 2006.06.08.

APPROVED BY CUSTOMER

歷 隆 企 業 有 限 公 司

SOFTECH ELECTRONICS CORP.

8/F, NO.82, SHING DE ROAD.,

SHAN CHUNG CITY 241, TAIPEI HSIEN, TAIWAN R.O.C.

TEL: 886-2-29952886

FAX: 886-2-29952523

■ APPLICATION

WLAN, Home RF, Bluetooth, etc.

■ FEATURES

■ Compact Size

Miniaturized SMD packaged in low profile and lightweight.

■ Wide Bandwidth

■ High Soldering Heat Resistance

High quality termination allows both flow and re-flow soldering methods to be applied.

■ Available in Tape and Reel Packaging for Automatic Mounting

■ No Ground Clearance to Save Real Estate

■ PRODUCT IDENTIFICATION

C B A - 0 8 0 4 - # # # x x - A 1

① Product Code

② Dimension Code

③ Series Type (### represents center frequency and xx represents material type)

④ Design Code

■ ELECTRICAL REQUIREMENTS

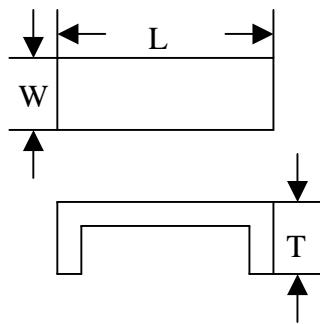
Part NO.	Frequency	Impedance	Bandwidth*	Gain*	VSWR	Polarization
CBA-0804-2G4S2-A1	2450 MHz	50 Ohms	>100 MHz	>1 dBi	3.0max.	Linear

*Depend on PCB layout.



MAG.LAYERS

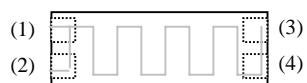
■ PRODUCT DIMENSION



L	W	T
8.0 ± 0.2	4.0 ± 0.2	3 ± 0.2

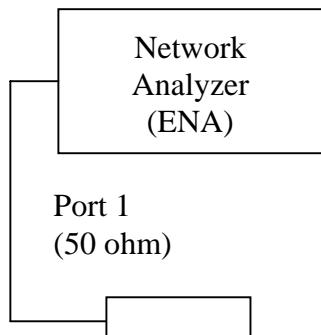
NOTE : Dimensions in mm

■ TERMINAL CONFIGURATION



- ① GND
- ② Feed Termination
- ③ N.C.
- ④ N.C.

■ MEASURING DIAGRAM

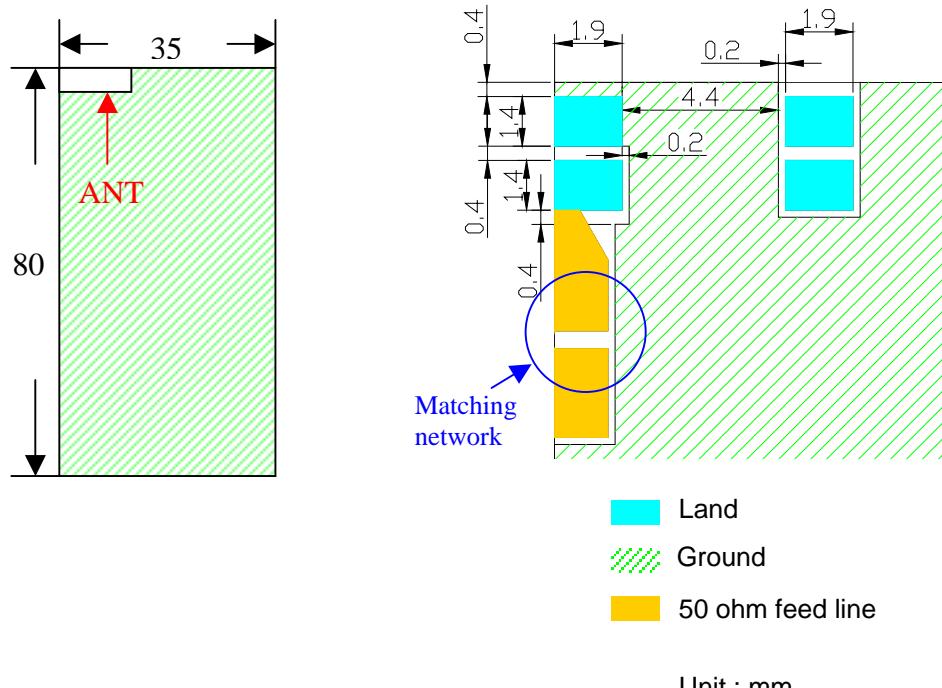


Test Instrument:
Agilent E5071A Network Analyzer

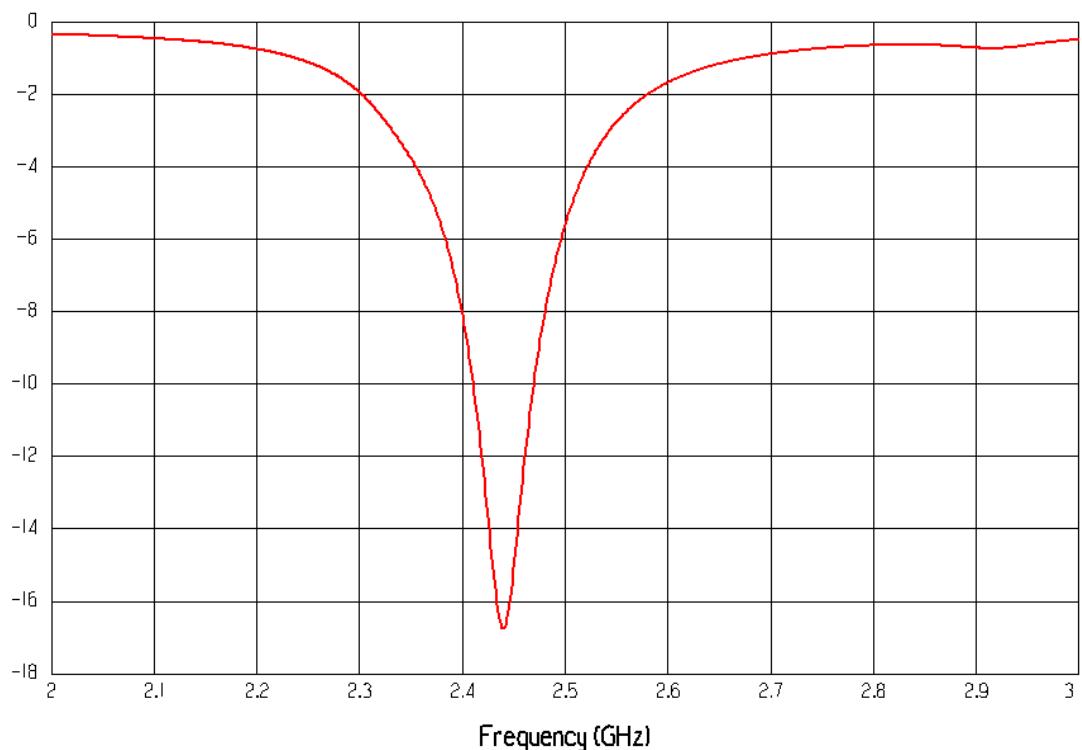


MAG.LAYERS

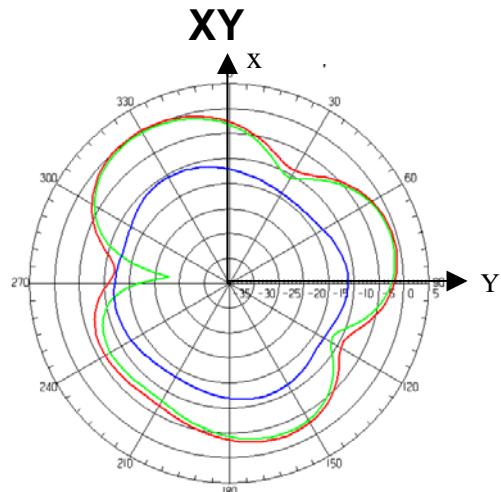
RECOMMENDED PCB LAYOUT



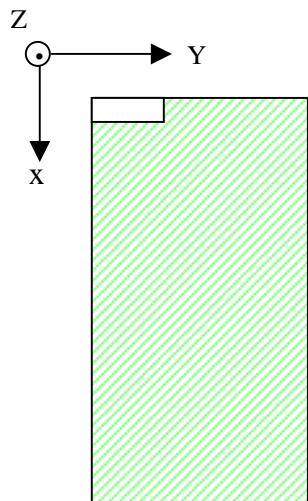
ELECTRICAL CHARACTERISTICS (T=25°C)



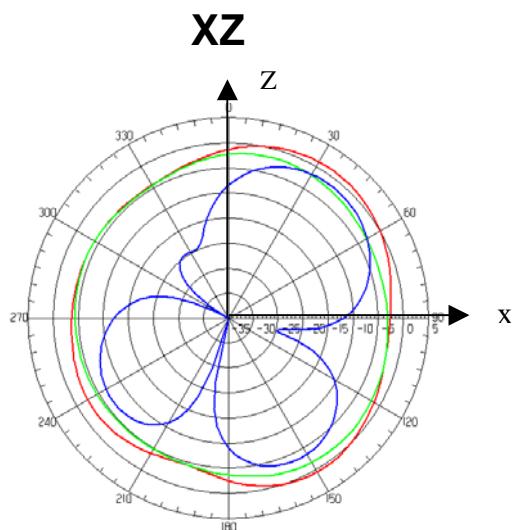
RADIATION PATTERN



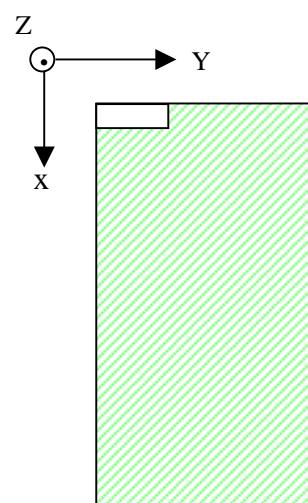
- Total
- Horizontal
- Vertical



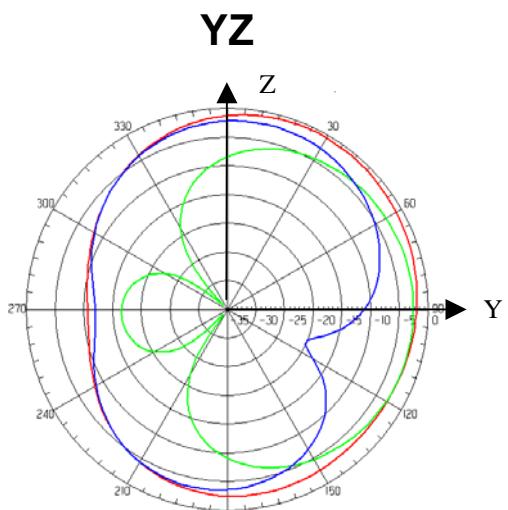
Peak Gain = 0.31076571 dBi



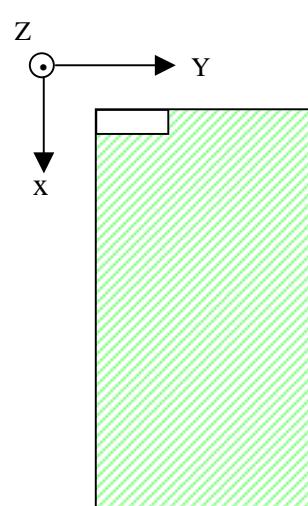
- Total
- Horizontal
- Vertical



Peak Gain = 1.1191249 dBi



- Total
- Horizontal
- Vertical

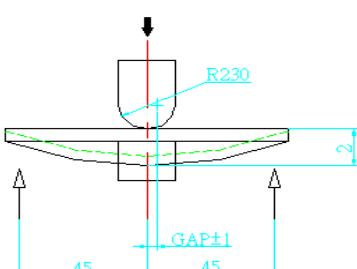


Peak Gain = -0.57884579 dBi



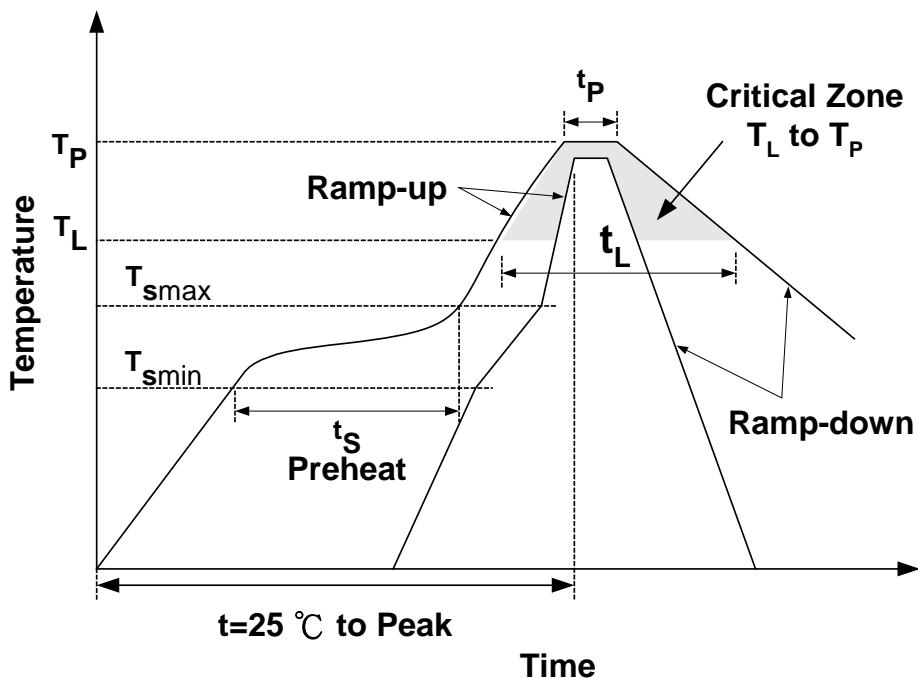
MAG.LAYERS

RELIABILITY TEST

Item	Condition	Specification
Thermal shock	-40°C ~ +85°C for 100 cycles each cycle being 30 min	No apparent damage Fulfill the electrical spec. after test
Humidity resistance	85±2°C, 80~90% R.H. for 500 hours	No apparent damage Fulfill the electrical spec. after test
High temperature resistance	+85±2°C for 500 hours	No apparent damage Fulfill the electrical spec. after test
Low temperature resistance	-40±3°C for 500 hours	No apparent damage Fulfill the electrical spec. after test
Vibration	10 Hz/min~55 Hz/min~10 Hz/min vibration frequency with 1.5 mm amplitude for two hours in x, y, z directions	No apparent damage
Drop shock	Dropped onto printed circuit board from 100cm height three times in x, y, z directions. The terminals shall be protected.	No apparent damage
Soldering heat resistance	Preheating temperature : 150±10°C Preheating time : 1 to 2 minutes Solder bath temperature : 260±5°C Bathing time : 5±0.5 seconds	No apparent damage
Bending test onto printed circuit board	Solder specimen LTCC components on the test printed circuit board (L: 100 x W: 40 x T: 1.6mm) in appended recommended PCB pattern. Apply the load in direction of the arrow until bending reaches 2 mm.  Unit: mm	No apparent damage
Solderability	The dipped surface of the terminal shall be at least 75% covered with solder after dipped in solder bath of 235±5°C for 3±0.5 seconds.	No apparent damage



RECOMMENDED REFLOW SOLDERING PROFILE



Profile Feature		Sn-Pb	Pb-Free
Preheat	t_s	60~120 seconds	60~180 seconds
	T_{smin}	100°C	150°C
	T_{smax}	150°C	200°C
Average ramp-up rate (T_{smax} to T_P)		3°C/second max.	3°C/second max.
Time main above	Temperature (T_L)	183°C	217°C
	Time (t_L)	60~150 seconds	60~150 seconds
Peak temperature (T_P)		230°C	250~255°C
Time within 5°C of actual peak temperature (t_P)		10 seconds	10 seconds
Ramp-down rate		6°C/sec max.	6°C/sec max.
Time 25°C to peak temperature		6 minutes max.	8 minutes max.

NOTES

The contents of this data sheet are subject to change without notice. Please confirm the specifications and delivery conditions when placing your order.



MAG.LAYERS



Mag Layers Scientific-Technics., Co., Ltd

Material description

Report No:GP/2006/01003-C

Mag. Layers certifiy below statement for material description
Component type :

I .Multilayer Ferrite Chip Bead and Inductor Series

II .Multilayer Common Mode Filters CMF Series

III .High Frequency Ceramic Chip Inductor HFI Series

IV .Low Temperature Cofired Ceramics Series

Compliant to Restriction of the use of certain hazardous substances in Electrical and Electronic Equipment (RoHS) and Sony SS-00259.

Terminal : Ag/Cu/Ni/Sn alloy ---- Lead free for alloy

Material testing report :

Name of material	Supplier Name	Pb	Hg	Cr+6	Cd	PBBs	PBDEs	Report NO
Ag Paste	EXOJET	N.D.	N.D.	N.D.	N.D.	N.D.	N.D.	CE/2005/96755 CE/2005/96756 CE/2005/96757
Copper (Cu layer)	NATURE	N.D.	N.D.	N.D.	N.D.	N.D.	N.D.	CV/2006/50020
Nickel (Ni layer)	KUEN TING	N.D.	N.D.	N.D.	N.D.	N.D.	N.D.	CV/2006/50019
Tin (Sn layer)	JAU JANQ	21.5	N.D.	N.D.	N.D.	N.D.	N.D.	KA/2005/80235/A-1

Prepared by : QC Dept. Miinshiung Hsu

Checked by : QC Manager Thomas Liao

Date : 2006 / 06 / 06

Form No:QAR014-A

Test Report

EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96755
Date : 2005/10/07
Page : 1 of 2

The following merchandise was (were) submitted and identified by the client as :

Type of Product : PASTE
Style/Item No : ML-5175, ML-5175A, ML-5175B, ML-5175S, ML-5175H,
ML-5175K, ML-5175A2, ML-5175B2, ML-5175S2,
ML-5175H2, ML-5175K2, ML-5175X1, ML-5175X2,
ML-5175X3, ML-5175X4, ML-5175X5, ML-5175X6
Sample Received : 2005/09/30
Testing Date : 2005/09/30 TO 2005/10/07

=====

Test Result

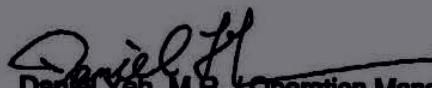
PART NAME NO.1 : BLACKISH GREEN PASTE (PLEASE REFER TO THE
PHOTO ATTACHED)

Test Item (s):	Unit	Method	MDL	Result	
				No. 1	
Cadmium (Cd)	ppm	ICP-AES after reference to EN 1122, method B:2001 or other acid digestion.	2	N.D.	

NOTE: (1) N.D. = Not detected (<MDL)

(2) ppm = mg/kg

(3) MDL = Method Detection Limit


Daniel Yeh, M.R. / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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Test Report

EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96755
Date : 2005/10/07
Page : 2 of 2



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Test Report

EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96756
Date : 2005/10/07
Page : 1 of 2

The following merchandise was (were) submitted and identified by the client as :

Type of Product : PASTE
Style/Item No : ML-5175, ML-5175A, ML-5175B, ML-5175S, ML-5175H,
ML-5175K, ML-5175A2, ML-5175B2, ML-5175S2,
ML-5175H2, ML-5175K2, ML-5175X1, ML-5175X2,
ML-5175X3, ML-5175X4, ML-5175X5, ML-5175X6
Sample Received : 2005/09/30
Testing Date : 2005/09/30 TO 2005/10/07

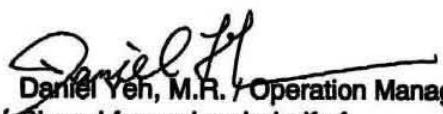
=====

Test Result

PART NAME NO.1 : BLACKISH GREEN PASTE (PLEASE REFER TO THE
PHOTO ATTACHED)

Test Item (s):	Unit	Method	MDL	Result	
				No. 1	
Lead (Pb)	ppm	ICP-AES after reference to US EPA 3050B or other acid digestion.	2	N.D.	

NOTE: (1) N.D. = Not detected (<MDL)
(2) ppm = mg/kg
(3) MDL = Method Detection Limit


Daniel Yeh, M.R. Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96756
Date : 2005/10/07
Page : 2 of 2



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EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96757
Date : 2005/10/07
Page : 1 of 4

The following merchandise was (were) submitted and identified by the client as :

Type of Product : PASTE
Style/Item No : ML-5175, ML-5175A, ML-5175B, ML-5175S, ML-5175H,
ML-5175K, ML-5175A2, ML-5175B2, ML-5175S2,
ML-5175H2, ML-5175K2, ML-5175X1, ML-5175X2,
ML-5175X3, ML-5175X4, ML-5175X5, ML-5175X6
Sample Received : 2005/09/30
Testing Date : 2005/09/30 TO 2005/10/07

=====

Test Result : - Please see the next page -



Daniel Yeh, M.R. / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96757
Date : 2005/10/07
Page : 2 of 4

Test Result

PART NAME NO.1 : BLACKISH GREEN PASTE (PLEASE REFER TO THE PHOTO ATTACHED)

Test Item (s):	Unit	Method	MDL	Result
				No.1
Monobromobiphenyl	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.
Dibromobiphenyl	%		0.0005	N.D.
Tribromobiphenyl	%		0.0005	N.D.
Tetrabromobiphenyl	%		0.0005	N.D.
Pentabromobiphenyl	%		0.0005	N.D.
Hexabromobiphenyl	%		0.0005	N.D.
Heptabromobiphenyl	%		0.0005	N.D.
Octabromobiphenyl	%		0.0005	N.D.
Nonabromobiphenyl	%		0.0005	N.D.
Decabromobiphenyl	%		0.0005	N.D.
Total PBBs (Polybrominated biphenyls)/ Sum of above	%		-	N.D.
Monobromobiphenyl ether	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	N.D.
Dibromobiphenyl ether	%		0.0005	N.D.
Tribromobiphenyl ether	%		0.0005	N.D.
Tetrabromobiphenyl ether	%		0.0005	N.D.
Pentabromobiphenyl ether	%		0.0005	N.D.
Hexabromobiphenyl ether	%		0.0005	N.D.
Heptabromobiphenyl ether	%		0.0005	N.D.
Octabromobiphenyl ether	%		0.0005	N.D.
Nonabromobiphenyl ether	%		0.0005	N.D.
Decabromobiphenyl ether	%		0.0005	N.D.
Total PBBEs(PBDEs) (Polybrominated biphenyl ethers)/ Sum of above	%		-	N.D.

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6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96757
Date : 2005/10/07
Page : 3 of 4

Test Item (s):	Unit	Method	MDL	Result	
				No.1	
Chromium VI (Cr+6)	ppm	UV-VIS after reference to US EPA 3060A.	2	N.D.	
Mercury (Hg)	ppm	ICP-AES after reference to US EPA 3052 or other acid digestion.	2	N.D.	

NOTE: (1) N.D. = Not detected (<MDL)

(2) ppm = mg/kg

(3) MDL = Method Detection Limit

(4) " - " = No Regulation

Test Report

EXOJET TECHNOLOGY CORPORATION
6F, NO. 22, TAI YUEN STREET, CHUPEI, HSINCHU,
TAIWAN (TAI YUEN HI-TECH IND. PARK)

Report No. : CE/2005/96757
Date : 2005/10/07
Page : 4 of 4



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Test Report

MAG. LAYERS SCIENTIFIC-TECHNICS CO., LTD.
18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

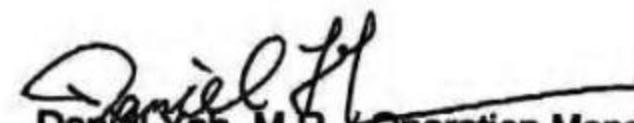
Report No. : CV/2006/50020
Date : 2006/06/06
Page : 1 of 4

The following merchandise was (were) submitted and identified by the client as :

Type of Product : PLATING Cu-DHP BALL
Style/Item No : Cu-DHP BALL
Sample Received : 2006/05/29
Testing Date : 2006/05/29 TO 2006/06/06

=====

Test Result : - Please see the next page -



Daniel Yeh, M.R. / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

Report No. : CV/2006/50020
Date : 2006/06/06
Page : 2 of 4

Test Result

PART NAME NO.1 : GOLDEN COLORED METAL

Test Item (s):	Unit	Method	MDL	Result
				No.1
Monobromobiphenyl	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS.	0.0005	N.D.
Dibromobiphenyl	%		0.0005	N.D.
Tribromobiphenyl	%		0.0005	N.D.
Tetrabromobiphenyl	%		0.0005	N.D.
Pentabromobiphenyl	%		0.0005	N.D.
Hexabromobiphenyl	%		0.0005	N.D.
Heptabromobiphenyl	%		0.0005	N.D.
Octabromobiphenyl	%		0.0005	N.D.
Nonabromobiphenyl	%		0.0005	N.D.
Decabromobiphenyl	%		0.0005	N.D.
Total PBBs (Polybrominated biphenyls)/Sum of above	%		-	N.D.
Monobromobiphenyl ether	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS.	0.0005	N.D.
Dibromobiphenyl ether	%		0.0005	N.D.
Tribromobiphenyl ether	%		0.0005	N.D.
Tetrabromobiphenyl ether	%		0.0005	N.D.
Pentabromobiphenyl ether	%		0.0005	N.D.
Hexabromobiphenyl ether	%		0.0005	N.D.
Heptabromobiphenyl ether	%		0.0005	N.D.
Octabromobiphenyl ether	%		0.0005	N.D.
Nonabromobiphenyl ether	%		0.0005	N.D.
Decabromobiphenyl ether	%		0.0005	N.D.
Total PBBEs(PBDEs) (Polybrominated biphenyl ethers)/Sum of above	%		-	N.D.
Total of Mono to Nona-brominated biphenyl ether. (Note 4)	%		-	N.D.

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18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

Report No. : CV/2006/50020
Date : 2006/06/06
Page : 3 of 4

Test Item (s):	Unit	Method	MDL	Result
				No.1
Chromium VI (Cr+6)	ppm	UV-VIS(US EPA 7196A) after reference to US EPA 3060A.	2	N.D.
Cadmium (Cd)	ppm	ICP-AES after reference to EN 1122, method B:2001 or other acid digestion.	2	N.D.
Mercury (Hg)	ppm	ICP-AES after reference to US EPA 3052 or other acid digestion.	2	N.D.
Lead (Pb)	ppm	ICP-AES after reference to US EPA 3050B or other acid digestion.	2	N.D.

NOTE: (1) N.D. = Not detected (<MDL)

(2) ppm = mg/kg

(3) MDL = Method Detection Limit

(4) Decabromobiphenyl ether (DecaBDE) in polymeric applications is exempted by
Commission Decision of 13 Oct 2005 amending Directive 2002/95/EC notified
under document 2005/717/EC.

(5) PBBEs=PBDEs=Polybrominated Diphenyl Ethers=PBDOs=PBBOs.

(6) " - " = Not Regulation

Test Report

MAG. LAYERS SCIENTIFIC-TECHNICS CO., LTD.
18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

Report No. : CV/2006/50020
Date : 2006/06/06
Page : 4 of 4



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Test Report

MAG. LAYERS SCIENTIFIC-TECHNICS CO., LTD.
18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

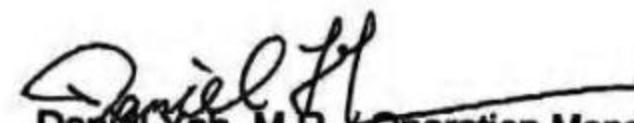
Report No. : CV/2006/50019
Date : 2006/06/06
Page : 1 of 4

The following merchandise was (were) submitted and identified by the client as :

Type of Product : PLATING Ni BALL
Style/Item No : Ni BALL
Sample Received : 2006/05/29
Testing Date : 2006/05/29 TO 2006/06/06

=====

Test Result : - Please see the next page -



Daniel Yeh, M.R. / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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Test Report

MAG. LAYERS SCIENTIFIC-TECHNICS CO., LTD.
18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

Report No. : CV/2006/50019
Date : 2006/06/06
Page : 2 of 4

Test Result

PART NAME NO.1 : GRAY METAL

Test Item (s):	Unit	Method	MDL	Result
				No.1
Monobromobiphenyl	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS.	0.0005	N.D.
Dibromobiphenyl	%		0.0005	N.D.
Tribromobiphenyl	%		0.0005	N.D.
Tetrabromobiphenyl	%		0.0005	N.D.
Pentabromobiphenyl	%		0.0005	N.D.
Hexabromobiphenyl	%		0.0005	N.D.
Heptabromobiphenyl	%		0.0005	N.D.
Octabromobiphenyl	%		0.0005	N.D.
Nonabromobiphenyl	%		0.0005	N.D.
Decabromobiphenyl	%		0.0005	N.D.
Total PBBs (Polybrominated biphenyls)/Sum of above	%		-	N.D.
Monobromobiphenyl ether	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS.	0.0005	N.D.
Dibromobiphenyl ether	%		0.0005	N.D.
Tribromobiphenyl ether	%		0.0005	N.D.
Tetrabromobiphenyl ether	%		0.0005	N.D.
Pentabromobiphenyl ether	%		0.0005	N.D.
Hexabromobiphenyl ether	%		0.0005	N.D.
Heptabromobiphenyl ether	%		0.0005	N.D.
Octabromobiphenyl ether	%		0.0005	N.D.
Nonabromobiphenyl ether	%		0.0005	N.D.
Decabromobiphenyl ether	%		0.0005	N.D.
Total PBBEs(PBDEs) (Polybrominated biphenyl ethers)/Sum of above	%		-	N.D.
Total of Mono to Nona-brominated biphenyl ether. (Note 4)	%		-	N.D.

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Test Report

MAG. LAYERS SCIENTIFIC-TECHNICS CO., LTD.
18 TZ-CHIANG RD., HSIN-CHU INDUSTRIAL PARK,
HUKOU, HSIN-CHU, TAIWAN 303, R. O. C.

Report No. : CV/2006/50019
Date : 2006/06/06
Page : 3 of 4

Test Item (s):	Unit	Method	MDL	Result
				No.1
Chromium VI (Cr+6)	ppm	UV-VIS(US EPA 7196A) after reference to US EPA 3060A.	2	N.D.
Cadmium (Cd)	ppm	ICP-AES after reference to EN 1122, method B:2001 or other acid digestion.	2	N.D.
Mercury (Hg)	ppm	ICP-AES after reference to US EPA 3052 or other acid digestion.	2	N.D.
Lead (Pb)	ppm	ICP-AES after reference to US EPA 3050B or other acid digestion.	2	N.D.

NOTE: (1) N.D. = Not detected (<MDL)

(2) ppm = mg/kg

(3) MDL = Method Detection Limit

(4) Decabromobiphenyl ether (DecaBDE) in polymeric applications is exempted by
Commission Decision of 13 Oct 2005 amending Directive 2002/95/EC notified
under document 2005/717/EC.

(5) PBBEs=PBDEs=Polybrominated Diphenyl Ethers=PBDOs=PBBOs.

(6) " - " = Not Regulation

Test Report

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Page : 4 of 4



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TEST REPORT

REPORT NO.KA/2005/80235/A-1
 DATE: 2005/8/9
 PAGE: 1 OF 1

THE FOLLOWING MERCHANDISE WAS(WERE) SUBMITTED AND IDENTIFIED BY THE CLIENT AS :

CLIENT : JAU JANQ ENTERPRISE CO.,LTD..
 PRODUCT DESCRIPTION : PURE TIN.
 SAMPLE : AS ATTACHED PHOTO .
 TESTING DATE : 2005/8/2 TO 2005/8/9 .
 SAMPLE RECEIVED : 2005/08/02.

WE HAVE TESTED THE SAMPLE(S) SUBMITTED AS REQUESTED AND THE FOLLOWING RESULTS WERE OBTAINED.

TEST ITEM(S)	UNIT	METHOD	DET. LMT	RESULT
CADMIUM	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT EN1122, METHOD B:2001.	2	n.d.
CHROMIUM VI	ppm	ANALYSIS BY US EPA 7196A WITH ADVANCE TREATMENT US EPA 3060A.	2	n.d.
MERCURY	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT US EPA 3052	2	n.d.
LEAD	ppm	ANALYSIS BY ICP-AES WITH ADVANCE TREATMENT US EPA 3050B	2	21.5
PBBs(Polybrominated biphenyls)	---	---	---	---
Bromobiphenyl	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	n.d.
Dibromobiphenyl	%		0.0005	n.d.
Tribromobiphenyl	%		0.0005	n.d.
Tetrabromobiphenyl	%		0.0005	n.d.
Pentabromobiphenyl	%		0.0005	n.d.
Hexabromobiphenyl	%		0.0005	n.d.
Heptabromobiphenyl	%		0.0005	n.d.
Octabromobiphenyl	%		0.0005	n.d.
Nonabromobiphenyl	%		0.0005	n.d.
Decabromobiphenyl	%		0.0005	n.d.
PBDEs(Polybrominated biphenyl ethers)	---	---	---	---
Monobromobiphenyl ether	%	With reference to USEPA3540C or USEPA3550C. Analysis was performed by HPLC/DAD, LC/MS or GC/MS. (prohibited by 2002/95/EC (RoHS), 83/264/EEC, and 76/769/EEC)	0.0005	n.d.
Dibromobiphenyl ether	%		0.0005	n.d.
Tribromobiphenyl ether	%		0.0005	n.d.
Tetrabromobiphenyl ether	%		0.0005	n.d.
Pentabromobiphenyl ether	%		0.0005	n.d.
Hexabromobiphenyl ether	%		0.0005	n.d.
Heptabromobiphenyl ether	%		0.0005	n.d.
Octabromobiphenyl ether	%		0.0005	n.d.
Nonabromobiphenyl ether	%		0.0005	n.d.
Decabromobiphenyl ether	%		0.0005	n.d.

NOTE : n.d. = not detected.

<END>



Kuellan Chen for
 Kuellan Chen / Asst. Supervisor
 Sign for and on behalf of
 SGS Taiwan Limited